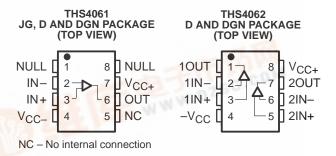
## 捷多邦,专业PCB打样工厂,24小**町州S406**1, THS4062 180-MHz HIGH-SPEED AMPLIFIERS

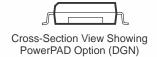
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- High Speed
  - 180 MHz Bandwidth (G = 1, -3 dB)
  - 400 V/μs Slew Rate
  - 40-ns Settling Time (0.1%)
- High Output Drive, I<sub>O</sub> = 115 mA (typ)
- Excellent Video Performance
  - 75 MHz 0.1 dB Bandwidth (G = 1)
  - 0.02% Differential Gain
  - 0.02° Differential Phase
- Very Low Distortion
  - THD = -72 dBc at f = 1 MHz
- Wide Range of Power Supplies
   V<sub>CC</sub> = ±5 V to ±15 V
- Available in Standard SOIC, MSOP
   PowerPAD™, JG, or FK Package
- Evaluation Module Available

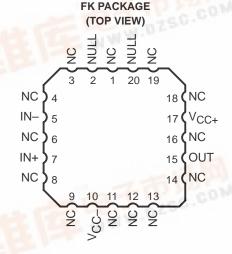
## description

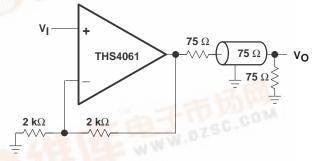
The THS4061 and THS4062 are generalpurpose, single/dual, high-speed voltage feedback amplifiers ideal for a wide range of applications including video, communication, and imaging. The devices offer very good ac performance with 180-MHz bandwidth, 400-V/µs slew rate, and 40-ns settling time (0.1%). The THS4061/2 are stable at all gains for both inverting and noninverting configurations. These amplifiers have a high output drive capability of 115 mA and draw only 7.8 mA supply current per channel. Excellent professional video results can be obtained with the low differential gain/phase errors of 0.02%/0.02° and wide 0.1 db flatness to 75 MHz. For applications requiring low distortion, the THS4061/2 is ideally suited with total harmonic distortion of -72 dBc at f = 1 MHz.





**THS4061** 





LINE DRIVER (G = 2)



CAUTION: The THS4061 and THS4062 provide ESD protection circuitry. However, permanent damage can still occur if this device is subjected to high-energy electrostatic discharges. Proper ESD precautions are recommended to avoid any performance degradation or loss of functionality



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

**U** TEXAS

PowerPAD is a trademark of Texas Insruments Incorporated.



	RELATED DEVICES
DEVICE	DESCRIPTION
THS4011/2	290-MHz Low Distortion High-Speed Amplifiers
THS4031/2	100-MHz Low Noise High Speed-Amplifiers
THS4061/2	180-MHz High-Speed Amplifiers

#### **AVAILABLE OPTIONS**

			PACKAGED	DEVICES			
TA	NUMBER OF CHANNELS	PLASTIC SMALL OUTLINE† (D)	PLASTIC MSOP† (DGN)	CERAMIC DIP (JG)	CHIP CARRIER (FK)	MSOP SYMBOL	EVALUATION MODULES
0°C to	1	THS4061CD	THS4061CDGN	_	_	TIABS	THS4061EVM
70°C	2	THS4062CD	THS4062CDGN	_	_	TIABM	THS4062EVM
–40°C to	1	THS4061ID	THS4061IDGN	_	_	TIABT	_
85°C	2	THS4062ID	THS4062IDGN	_	_	TIABN	_
–55°C to 125°C	1	_	_	THS4061MJG	THS4061MFK	_	_

<sup>†</sup> The D and DGN packages are available taped and reeled. Add an R suffix to the device type (i.e., THS4061CDGNR).

## functional block diagram

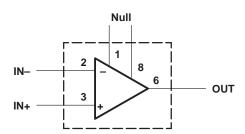


Figure 1. THS4061 - Single Channel

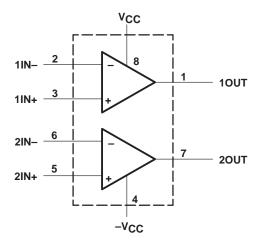


Figure 2. THS4062 - Dual Channel



## THS4061, THS4062 180-MHz HIGH-SPEED AMPLIFIERS

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## absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> + to V <sub>CC</sub>		33 V
Output current, IO		150 mA
Differential input voltage, V <sub>IO</sub>		±4 V
Continuous total power dissipation		See Dissipation Rating Table
Maximum junction temperature, T <sub>J</sub>		150°C
Operating free-air temperature, T <sub>A</sub> :	C-suffix	0°C to 70°C
	I-suffix	–40°C to 85°C
	M-suffix	–55°C to 125°C
Storage temperature, T <sub>stg</sub>		65°C to 150°C
	h) from case for 10 seconds, D and DGN p	
Lead temperature 1,6 mm (1/16 inc	h) from case for 60 seconds, JG package	300°C
Case temperature for 60 seconds, I	FK package	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
D	740 mW	6 mW/°C	475 mW	385 mW	_
DGN <sup>‡</sup>	2.14 W	17.1 mW/°C	1.37 W	1.11 W	_
JG	1057 mW	8.4 mW/°C	627 mW	546 mW	210 mW
FK	1375 mW	11 mW/°C	880 mW	715 mW	275 mW

<sup>&</sup>lt;sup>‡</sup> The DGN package incorporates a PowerPAD on the underside of the device. This acts as a heatsink and must be connected to a thermal dissipation plane for proper power dissipation. Failure to do so can result in exceeding the maximum specified junction temperature, which could permanently damage the device.

## recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage Vee Land Vee	Dual supply	±4.5		±16	\/
Supply voltage, V <sub>CC</sub> + and V <sub>CC</sub> -	Single supply	9		32	V
	C-suffix	0		70	
Operating free-air temperature, TA	I-suffix	-40		85	°C
	M-suffix	-55		125	



## THS4061, THS4062 180-MHz HIGH-SPEED AMPLIFIERS

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## electrical characteristics at T<sub>A</sub> = 25°C, V<sub>CC</sub> = $\pm 15$ V, R<sub>L</sub> = 150 $\Omega$ (unless otherwise noted)

## dynamic performance

PARAMETER		TEST CONDITIONS <sup>†</sup>		THS4061C/I, THS4062C/I			UNIT	
				MIN	TYP	MAX		
	Dynamic performance small-signal bandwidth (–3 dB)	$V_{CC} = \pm 5 \text{ V}$	Gain = 1		180		MHz	
		$V_{CC} = \pm 15 \text{ V}$	Gain = -1	50			MHz	
BW	banaman ( o ab)	$V_{CC} = \pm 5 \text{ V}$	Gaiii = -1	50				
	Bandwidth for 0.1 dB flatness	$V_{CC} = \pm 15 \text{ V}$	Gain = 1	75			MHz	
	Bandwidth for 0.1 dB nathess	$V_{CC} = \pm 5 \text{ V}$	Gaiii = 1		20		IVII IZ	
SR	Slew rate	$V_{CC} = \pm 15 \text{ V}$	Gain = -1		400		\//va	
JOIN .	Jew rate	$V_{CC} = \pm 5 \text{ V}$	Gaill = -1		350		V/μs	
	Settling time to 0.1%	$V_{CC} = \pm 15 \text{ V},  5-\text{V step } (0 \text{ V to } 5 \text{ V})$	Gain = -1		40		ns	
ļ.	Setting time to 0.176	$V_{CC} = \pm 5 \text{ V}, \qquad V_{O} = -2.5 \text{ V to } 2.5 \text{ V},$	Gaill = -1		40		1 115	
t <sub>S</sub>	Settling time to 0.01%	$V_{CC} = \pm 15 \text{ V},  5-\text{V step } (0 \text{ V to } 5 \text{ V})$	Gain = -1		140	·	ns	
	Setting time to 0.01%	$V_{CC} = \pm 5 \text{ V}, \qquad V_{O} = -2.5 \text{ V to } 2.5 \text{ V},$	Gaiii = -1		150	·		

<sup>†</sup> Full range =  $0^{\circ}$ C to  $70^{\circ}$ C for C suffix and  $-40^{\circ}$ C to  $85^{\circ}$ C for I suffix

## noise/distortion performance

	PARAMETER		TEST CONDITIONS†		THS4061C/I, THS4062C/I			UNIT
					MIN -	TYP N	ΛAΧ	
THD	Total harmonic distortion	f = 1 MHz				-72		dBc
Vn	Input voltage noise	f = 10 kHz,	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$			14.5		nV/√Hz
In	Input current noise	f = 10 kHz,	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$			1.6		pA/√Hz
	Differential gain arror	Gain = 2,	NTSC, 40 IRE modulation	V <sub>CC</sub> = ±15 V	(	0.02 %		
	Differential gain error	Gairi = 2,	N130, 40 IKE Modulation	V <sub>CC</sub> = ±5 V	(	0.02 %		
	Differential phase array	Coin	NTCC 40 IDE modulation	V <sub>CC</sub> = ±15 V	0	).02°		
	Differential phase error	Gain = 2,	NTSC, 40 IRE modulation	V <sub>CC</sub> = ±5 V	0	).06°		
	Channel-to-channel crosstalk (THS4062 only)	V <sub>CC</sub> = ±5 V c	or ±15 V, f = 1 MHz			65		dB

<sup>†</sup> Full range = 0°C to 70°C for C suffix and -40°C to 85°C for I suffix

## dc performance

	PARAMETER	TEST CONDITIONS <sup>†</sup>			THS4061C/I, THS4062C/I		
				MIN	TYP	MAX	
		T <sub>A</sub> = 25°C		5	15		V/mV
	Open loop gain	$V_{CC} = \pm 15 \text{ V},  V_{O} = \pm 10 \text{ V},  R_{L} = 1 \text{ k}\Omega$	T <sub>A</sub> = full range	4			V/IIIV
		Voc = +5 // Vo = +2 5 // Pr = 1 kO	T <sub>A</sub> = 25°C	2.5	8	V/mV	
		$V_{CC} = \pm 5 \text{ V}, \qquad V_{O} = \pm 2.5 \text{ V},  R_{L} = 1 \text{ k}\Omega$	T <sub>A</sub> = full range	2		V/IIIV	
\/	Input offset voltage	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	T. full rongs		2.5	8	mV
Vos	Offset drift	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	T <sub>A</sub> = full range		15		μV/°C
I <sub>IB</sub>	Input bias current	V <sub>CC</sub> = ±5 V or ±15 V	T <sub>A</sub> = full range		3	6	μА
los	Input offset current	V <sub>CC</sub> = ±5 V or ±15 V	T <sub>A</sub> = full range		75	250	nA
	Offset current drift	T <sub>A</sub> = full range			0.3		nA/°C

<sup>†</sup> Full range = 0°C to 70°C for C suffix and -40°C to 85°C for I suffix



# electrical characteristics at T<sub>A</sub> = 25 °C, V<sub>CC</sub> = $\pm$ 15 V, R<sub>L</sub> = 150 $\Omega$ (unless otherwise noted) (continued)

## input characteristics

PARAMETER		т	TEST CONDITIONS†			THS4061C/I, THS4062C/I		
					MIN	TYP	MAX	
V. 0.5	Common-mode input voltage range	$V_{CC} = \pm 15 \text{ V}$			±13.8	±14.1		V
VICR	Common-mode input voltage range	$V_{CC} = \pm 5 \text{ V}$				±4.3		
CMRR	Common mode rejection ratio	$V_{CC} = \pm 15 \text{ V},$	$V_{ICR} = \pm 12 V$	T full rongo	70	110		dB
CIVIKK	Common mode rejection ratio	$V_{CC} = \pm 5 \text{ V},$	V <sub>ICR</sub> = ±2.5 V	T <sub>A</sub> = full range	70	95		l as
R <sub>I</sub>	Input resistance					1		МΩ
Ci	Input capacitance					2		pF

<sup>†</sup> Full range = 0°C to 70°C for C suffix and -40°C to 85°C for I suffix

## output characteristics

PARAMETER		TEST CONDITIONS†			THS4061C/I, THS4062C/I		
						MAX	]
		V <sub>CC</sub> = ±15 V	$R_L = 250 \Omega$	±11.5	±12.5		V
\ <sub>\/</sub> -	Output voltage swing	$V_{CC} = \pm 5 \text{ V}$	$R_L = 150 \Omega$	±3.2	±3.5		V
Vo	Output voltage swing	V <sub>CC</sub> = ±15 V	$R_1 = 1 k\Omega$	±13	±13.5		V
		$V_{CC} = \pm 5 \text{ V}$	K	±3.5	±3.7		V
la	Output current	V <sub>CC</sub> = ±15 V	R <sub>1</sub> = 20 Ω	80	115		m /\
10	Output current	V <sub>CC</sub> = ±5 V	KL = 20 12	50	75		mA
I <sub>SC</sub>	Short-circuit current	V <sub>CC</sub> = ±15 V	·		150		mA
RO	Output resistance	Open loop			12		Ω

<sup>†</sup> Full range = 0°C to 70°C for C suffix and -40°C to 85°C for I suffix

## power supply

PARAMETER		TEST CONDITIONS†			THS4061C/I, THS4062C/I			
				MIN TYP MA			1 1	
V Cumphing the reason of the reason		Dual supply		±4.5		±16.5	V	
Vcc	Supply voltage operating range	Single supply		9		33	v	
	Ovicement ourset (new explifier)	V <sub>CC</sub> = ±15 V	T 6.11		7.8	10.5	^	
Icc	Quiescent current (per amplifier)	V <sub>CC</sub> = ±5 V	T <sub>A</sub> = full range		7.3	10	mA	
Denn	Device cumply rejection ratio	V 15 V or 145 V	T <sub>A</sub> = 25°C	70	78		dD	
PSRR	Power supply rejection ratio	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	T <sub>A</sub> = full range	68			dB	

<sup>†</sup> Full range = 0°C to 70°C for C suffix and -40°C to 85°C for I suffix



## THS4061, THS4062 180-MHz HIGH-SPEED AMPLIFIERS

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# electrical characteristics at T<sub>A</sub> = 25°C, V<sub>CC</sub> = $\pm$ 15 V, R<sub>L</sub> = 150 $\Omega$ (unless otherwise noted)

## dynamic performance

	PARAMETER				TH	//	UNIT		
	PARAMETER		TEST CONDITIONS†		MIN	TYP	MAX		
	Unity-gain bandwidth	Closed loop,	R <sub>L</sub> = 1 kΩ	$V_{CC} = \pm 15 \text{ V}$	*140	180		MHz	
	Dynamic performance small-signal	$V_{CC} = \pm 15 \text{ V}$		Gain = 1		180			
		$V_{CC} = \pm 5 \text{ V}$		Gairr = 1		180		MHz	
BW	bandwidth (-3 dB)	V <sub>CC</sub> = ±15 V		Gain = -1 50			MHz		
		$V_{CC} = \pm 5 \text{ V}$		Gaiii = -1		50		] IVITZ	
	Bandwidth for 0.1 dB flatness	$V_{CC} = \pm 15 \text{ V}$		Gain = 1		75		MHz	
	Dandwidth for 0.1 db flatfless	$V_{CC} = \pm 5 \text{ V}$		Gaiii = 1		20			
SR	Slew rate	V <sub>CC</sub> = ±15 V	$R_L = 1 k\Omega$		*400	500		V/μs	
	Settling time to 0.1%	$V_{CC} = \pm 15 \text{ V},$	5-V step (0 V to 5 V)	Gain = -1		40			
<b>.</b>	Settling time to 0.1%	$V_{CC} = \pm 5 \text{ V},$	$V_0 = -2.5 \text{ V to } 2.5 \text{ V},$	Gaiii = -1	50 75 20 *400 500	ns			
t <sub>S</sub>	Cattling time to 0.040/	$V_{CC} = \pm 15 \text{ V},$	5-V step (0 V to 5 V)	Gain = -1		140		ns	
	Settling time to 0.01%	$V_{CC} = \pm 5 \text{ V},$	$V_0 = -2.5 \text{ V to } 2.5 \text{ V},$	Gaiii = -1		150			

<sup>†</sup> Full range =  $-55^{\circ}$ C to 125°C for M suffix

## noise/distortion performance

PARAMETER TEST CONDITIONST				THS4061M			UNIT	
PARAMETER			TEST CONDITIONS <sup>†</sup>			TYP	MAX	UNIT
THD	Total harmonic distortion	f = 1 MHz				-72		dBc
٧n	Input voltage noise	f = 10 kHz,	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$			14.5		nV/√ <del>Hz</del>
In	Input current noise	f = 10 kHz,	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$			1.6		pA/√ <del>Hz</del>
	Differential gain arror	Differential pair away		V <sub>CC</sub> = ±15 V		0.02		%
	Differential gain error	Gain = 2,	NTSC, 40 IRE Modulation	V <sub>CC</sub> = ±5 V	0.02			70
	Differential phase error	Gain = 2,	NTSC, 40 IRE Modulation	V <sub>CC</sub> = ±15 V		0.02°		
		Gairi = 2, N130, 40 IRE Modulation		V <sub>CC</sub> = ±5 V		0.06°		

<sup>†</sup> Full range = -55°C to 125°C for M suffix

#### dc performance

PARAMETER		TEST CONDITIONS†			THS4061M			UNIT
					MIN	TYP	MAX	CIVIT
	Open loop gain	$V_{CC} = \pm 15 \text{ V},  V_{O} = \pm 10 \text{ V},$	$R_L = 1 \text{ k}\Omega$	T full range	5	9		V/mV
Open loop gain		$V_{CC} = \pm 5 \text{ V}, \qquad V_{O} = \pm 2.5 \text{ V},  R_{L} = 1 \text{ k}\Omega$		T <sub>A</sub> = full range	2.5	6		V/IIIV
VIO	Input offset voltage	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$ RL	R <sub>L</sub> = 1 kΩ	T <sub>A</sub> = 25°C		2.5	8	mV
				T <sub>A</sub> = full range			9	mV
	Offset drift	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	R <sub>L</sub> = 1 kΩ	T <sub>A</sub> = full range		15		μV/°C
I <sub>IB</sub>	Input bias current	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	R <sub>L</sub> = 1 kΩ	T <sub>A</sub> = full range		3	6	μΑ
I <sub>IO</sub>	Input offset current	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	R <sub>L</sub> = 1 kΩ	T <sub>A</sub> = full range		75	250	nA
	Offset current drift	$V_{CC} = \pm 5 \text{ V or } \pm 15 \text{ V}$	R <sub>L</sub> = 1 kΩ	T <sub>A</sub> = full range		0.3	·	nA/°C

<sup>†</sup> Full range = -55°C to 125°C for M suffix



<sup>\*</sup>This parameter is not tested.

# electrical characteristics at $T_A$ = full range, $V_{CC}$ = $\pm 15$ V, $R_L$ = 1 k $\Omega$ (unless otherwise noted) (continued)

## input characteristics

	PARAMETER	TEST SOMETISMS		THS4061M		
PARAMETER		TEST CONDITIONS <sup>†</sup>	MIN	TYP	MAX	UNIT
\ /	Common-mode input voltage range	$V_{CC} = \pm 15 \text{ V}$	±13.8	±14.1		V
VICR		$V_{CC} = \pm 5 \text{ V}$	±3.8	±4.3		
CMRR	Common mode rejection ratio	$V_{CC} = \pm 15 \text{ V}, \qquad V_{ICR} = \pm 12 \text{ V}$	70	86		dB
CIVIKK	Common mode rejection ratio	$V_{CC} = \pm 5 \text{ V}, \qquad V_{ICR} = \pm 2.5 \text{ V}$	80	90		uБ
R <sub>I</sub>	Input resistance			1		ΜΩ
Ci	Input capacitance			2		pF

<sup>†</sup> Full range = -55°C to 125°C for M suffix

## output characteristics

PARAMETER		TEST CONDITIONS†		THS4061M			UNIT
				MIN	TYP	MAX	ONII
		V <sub>CC</sub> = ±15 V	R <sub>L</sub> = 250 Ω	±12	±13.1		V
Vo	Output voltage ewing	V <sub>CC</sub> = ±5 V	R <sub>L</sub> = 150 Ω	±3.2	±3.5		V
	Output voltage swing	V <sub>CC</sub> = ±15 V	R <sub>L</sub> = 1 kΩ	±13	±13.5		V
		V <sub>CC</sub> = ±5 V		±3.5	±3.7		
1-	Output ourropt	V <sub>CC</sub> = ±15 V	R <sub>L</sub> = 20 Ω	70	115		mA
10	Output current	V <sub>CC</sub> = ±5 V		50	75		l IIIA
I <sub>SC</sub>	Short-circuit current	V <sub>CC</sub> = ±15 V	T <sub>A</sub> = 25°C		150		mA
RO	Output resistance	Open loop	·		12		Ω

<sup>†</sup> Full range = -55°C to 125°C for M suffix

## power supply

PARAMETER		TEST SOMBITIONS!		THS4061M			UNIT
	PARAMETER	TEST CONDITIONS <sup>†</sup>		MIN	TYP	MAX	UNIT
Vac	Supply voltage operating range	Dual supply		±4.5		±16.5	V
Vcc	Supply voltage operating range	Single supply		9		33	
	C Quiescent current	V <sub>CC</sub> = ±15 V	$T_{A} = 25^{\circ}C$ $T_{A} = 25^{\circ}C$ $T_{A} = \text{full range}$		7.8	9	mA
		$V_{CC} = \pm 5 \text{ V}$			7.3	8.5	
Icc		V <sub>CC</sub> = ±15 V				11	IIIA
		V <sub>CC</sub> = ±5 V				10.5	
PSRR	Power supply rejection ratio	V <sub>CC</sub> = ±5 V or ±15 V	T <sub>A</sub> = 25°C	76	80	·	dB
FORK			T <sub>A</sub> = full range	74	78		uБ

<sup>†</sup> Full range = –55°C to 125°C for M suffix



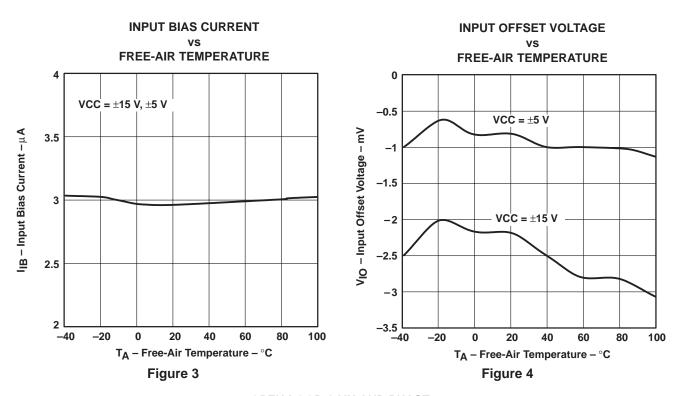
# THS4061, THS4062 180-MHz HIGH-SPEED AMPLIFIERS

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## **TYPICAL CHARACTERISTICS**

			FIGURE
I <sub>IB</sub>	Input bias current	vs Free-air temperature	3
VIO	Input offset voltage	vs Free-air temperature	4
	Open-loop gain	vs Frequency	5
	Phase	vs Frequency	5
	Differential gain	vs Number of loads	6, 8
	Differential phase	vs Number of loads	7, 9
	Closed-loop gain	vs Frequency	10, 11
	Output Amplitude	vs Frequency	12, 13
CMRR	Common-mode rejection ratio	vs Frequency	14
DCDD	Davida avanh, miastica natio	vs Frequency	15
PSRR	Power-supply rejection ratio	vs Free-air temperature	16
V <sub>O(PP)</sub>	Output voltage swing	vs Supply voltage	17
ICC	Supply current	vs Free-air temperature	18
E <sub>nv</sub>	Noise spectral density	vs Frequency	19
THD	Total harmonic distortion	vs Frequency	20, 21

#### **TYPICAL CHARACTERISTICS**



# OPEN-LOOP GAIN AND PHASE

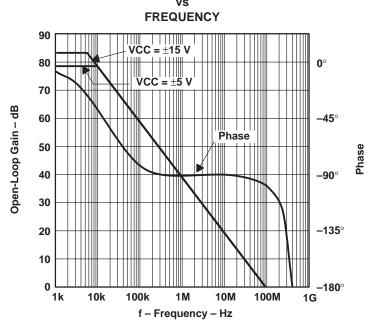
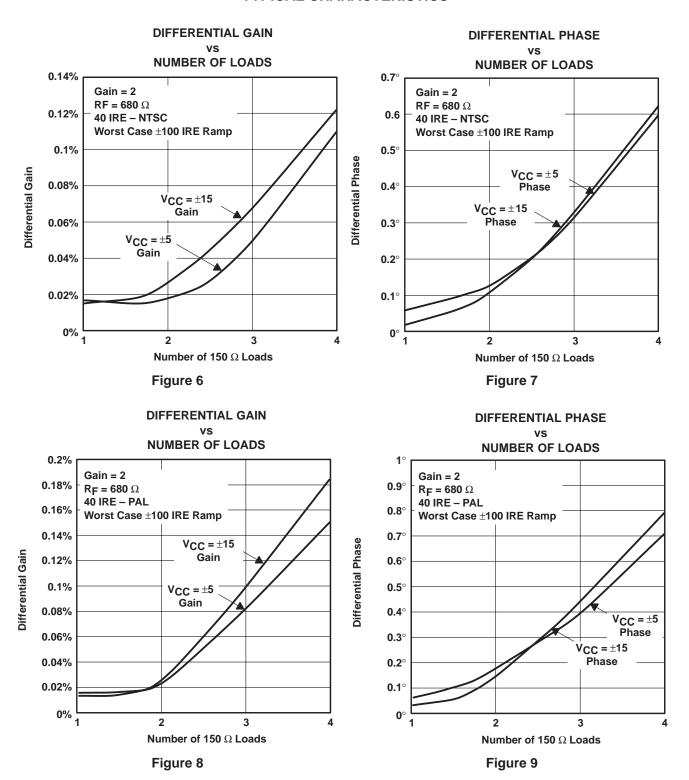


Figure 5

#### TYPICAL CHARACTERISTICS





**CLOSED-LOOP GAIN** 

#### **TYPICAL CHARACTERISTICS**

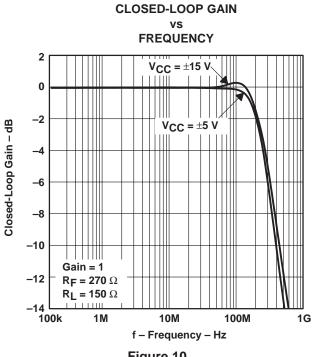
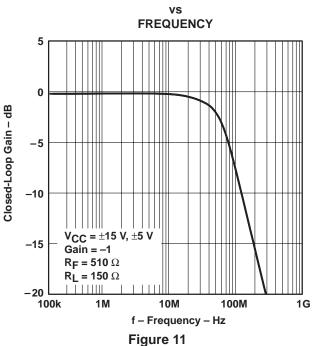
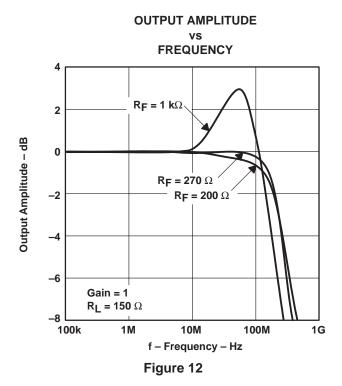
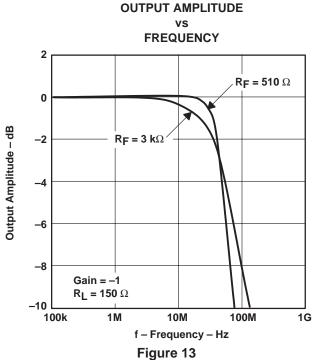


Figure 10



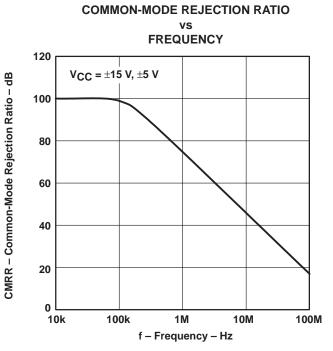


-8 Gain = -1100k 1M

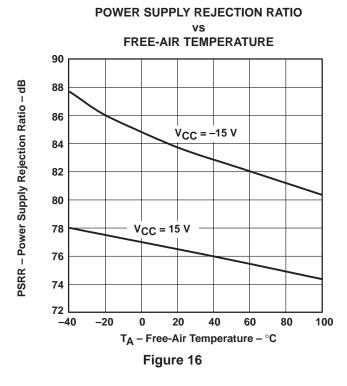


TEXAS

#### **TYPICAL CHARACTERISTICS**







## POWER SUPPLY REJECTION RATIO

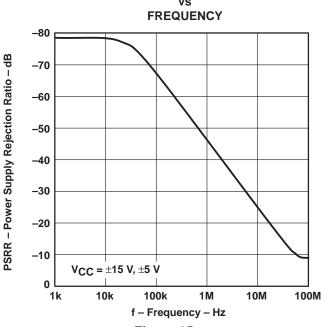
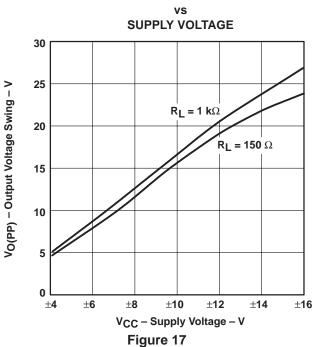


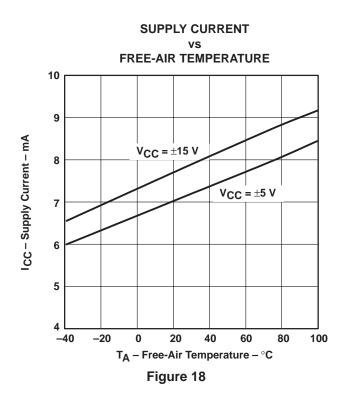
Figure 15

## **OUTPUT VOLTAGE SWING**

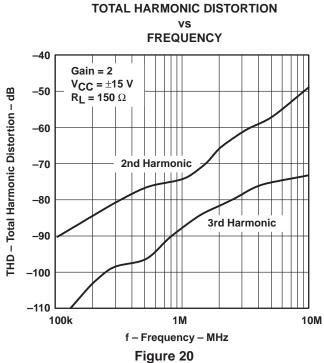


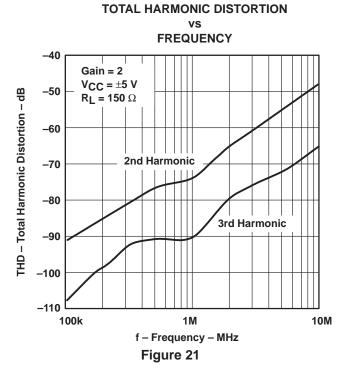


#### **TYPICAL CHARACTERISTICS**



**NOISE SPECTRAL DENSITY FREQUENCY** 180 T<sub>A</sub> = 25°C 160 E<sub>nv</sub> − Noise Spectral Density − nV/√Hz 140 120 100 80 60 40 20 0 10 100 1k 10k 100k f - Frequency - Hz Figure 19





## theory of operation

The THS406x is a high speed, operational amplifier configured in a voltage feedback architecture. It is built using a 30-V, dielectrically isolated, complementary bipolar process with NPN and PNP transistors possessing  $f_Ts$  of several GHz. This results in an exceptionally high performance amplifier that has a wide bandwidth, high slew rate, fast settling time, and low distortion. A simplified schematic is shown in Figure 22.

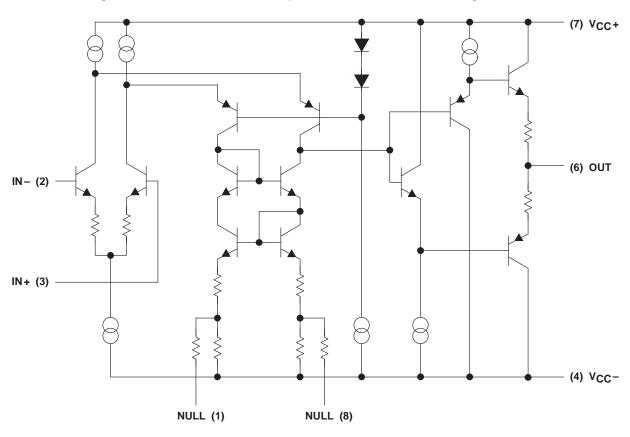


Figure 22. THS4061 Simplified Schematic

## offset nulling

The THS4061 has very low input offset voltage for a high-speed amplifier. However, if additional correction is required, an offset nulling function has been provided. By placing a potentiometer between terminals 1 and 8 and tying the wiper to the negative supply, the input offset can be adjusted. This is shown in Figure 23.

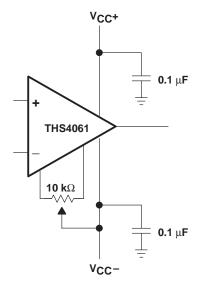


Figure 23. Offset Nulling Schematic

## optimizing unity gain response

Internal frequency compensation of the THS406x was selected to provide very wideband performance yet still maintain stability when operated in a noninverting unity gain configuration. When amplifiers are compensated in this manner there is usually peaking in the closed loop response and some ringing in the step response for very fast input edges, depending upon the application. This is because a minimum phase margin is maintained for the G=+1 configuration. For optimum settling time and minimum ringing, a feedback resistor of  $270\,\Omega$  should be used as shown in Figure 24. Additional capacitance can also be used in parallel with the feedback resistance if even finer optimization is required.

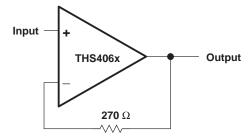


Figure 24. Noninverting, Unity Gain Schematic



#### driving a capacitive load

Driving capacitive loads with high performance amplifiers is not a problem as long as certain precautions are taken. The first is to realize that the THS406x has been internally compensated to maximize its bandwidth and slew rate performance. When the amplifier is compensated in this manner, capacitive loading directly on the output will decrease the device's phase margin leading to high frequency ringing or oscillations. Therefore, for capacitive loads of greater than 10 pF, it is recommended that a resistor be placed in series with the output of the amplifier, as shown in Figure 25. A minimum value of 20  $\Omega$  should work well for most applications. For example, in 75- $\Omega$  transmission systems, setting the series resistor value to 75  $\Omega$  both isolates any capacitance loading and provides the proper line impedance matching at the source end.

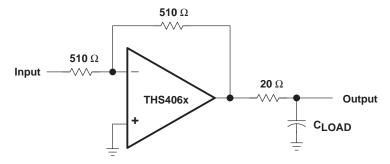


Figure 25. Driving a Capacitive Load

#### circuit layout considerations

In order to achieve the levels of high frequency performance of the THS406x, it is essential that proper printed-circuit board high frequency design techniques be followed. A general set of guidelines is given below. In addition, a THS406x evaluation board is available to use as a guide for layout or for evaluating the device performance.

- Ground planes It is highly recommended that a ground plane be used on the board to provide all
  components with a low inductive ground connection. However, in the areas of the amplifier inputs and
  output, the ground plane can be removed to minimize the stray capacitance.
- Proper power supply decoupling Use a 6.8-μF tantalum capacitor in parallel with a 0.1-μF ceramic capacitor on each supply terminal. It may be possible to share the tantalum among several amplifiers depending on the application, but a 0.1-μF ceramic capacitor should always be used on the supply terminal of every amplifier. In addition, the 0.1-μF capacitor should be placed as close as possible to the supply terminal. As this distances increases, the inductance in the connecting trace makes the capacitor less effective. The designer should strive for distances of less than 0.1 inches between the device power terminals and the ceramic capacitors.
- Sockets Sockets are not recommended for high-speed operational amplifiers. The additional lead inductance in the socket pins will often lead to stability problems. Surface-mount packages soldered directly to the printed-circuit board is the best implementation.
- Short trace runs/compact part placements Optimum high frequency performance is achieved when stray series inductance has been minimized. To realize this, the circuit layout should be made as compact as possible thereby minimizing the length of all trace runs. Particular attention should be paid to the inverting input of the amplifier. Its length should be kept as short as possible. This will help to minimize stray capacitance at the input of the amplifier.



#### circuit layout considerations (continued)

 Surface-mount passive components – Using surface-mount passive components is recommended for high-frequency amplifier circuits for several reasons. First, because of the extremely low lead inductance of surface-mount components, the problem with stray series inductance is greatly reduced. Second, the small size of surface-mount components naturally leads to a more compact layout, thereby minimizing both stray inductance and capacitance. If leaded components are used, it is recommended that the lead lengths be kept as short as possible.

#### evaluation board

An evaluation board is available for the THS4061 (literature number SLOP226) and THS4062 (literaure number SLOP235). This board has been configured for very low parasitic capacitance in order to realize the full performance of the amplifier. A schematic of the evaluation board is shown in Figure 26. The circuitry has been designed so that the amplifier may be used in either an inverting or noninverting configuration. To order the evaluation board contact your local TI sales office or distributor. For more detailed information, refer to the THS4061 EVM User's Manual (literature number SLOU038) or the THS4062 EVM User's Manual (literature number SLOU040)

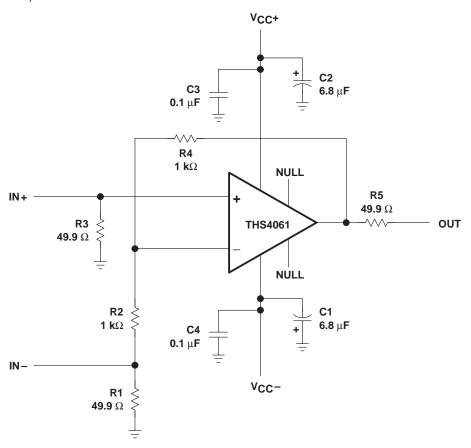


Figure 26. THS4061 Evaluation Board Schematic

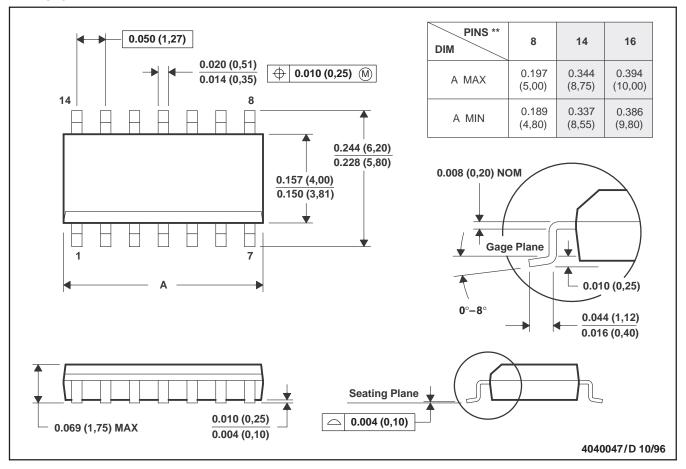


#### **MECHANICAL INFORMATION**

## D (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE

#### 14 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

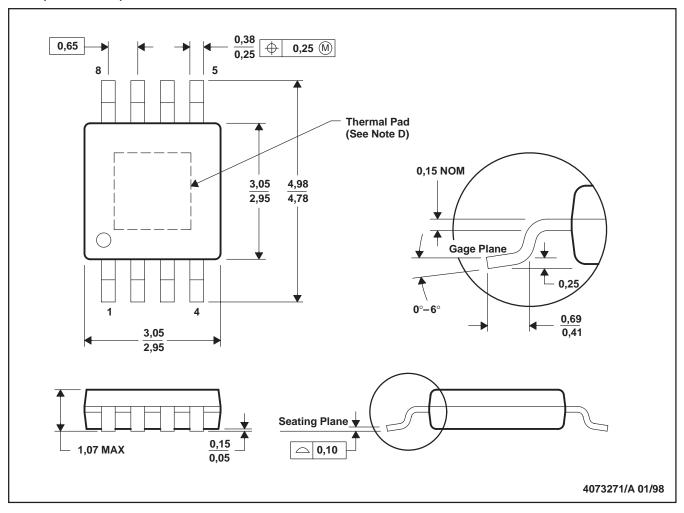
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012



## **MECHANICAL INFORMATION**

## DGN (S-PDSO-G8)

#### PowerPAD™ PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions include mold flash or protrusions.
- D. The package thermal performance may be enhanced by attaching an external heat sink to the thermal pad. This pad is electrically and thermally connected to the backside of the die and possibly selected leads.
- E. Falls within JEDEC MO-187

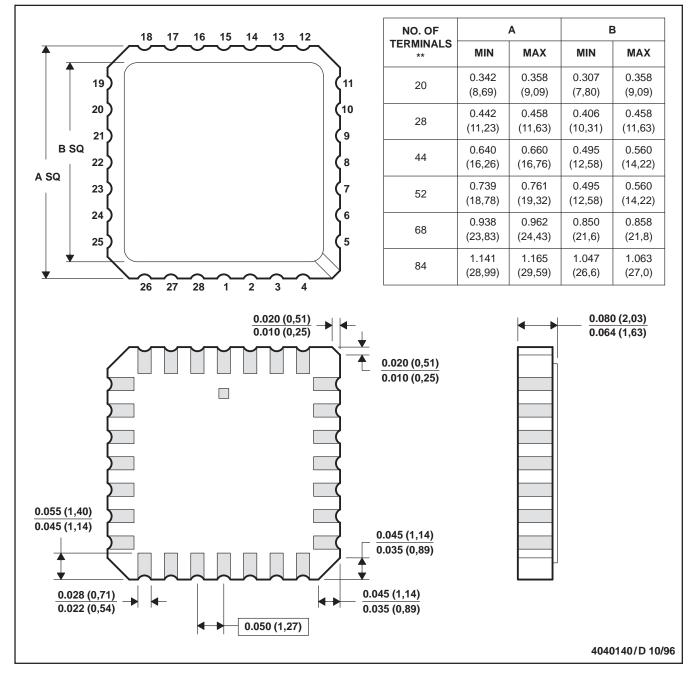


#### **MECHANICAL INFORMATION**

## FK (S-CQCC-N\*\*)

#### 28 TERMINAL SHOWN

#### LEADLESS CERAMIC CHIP CARRIER



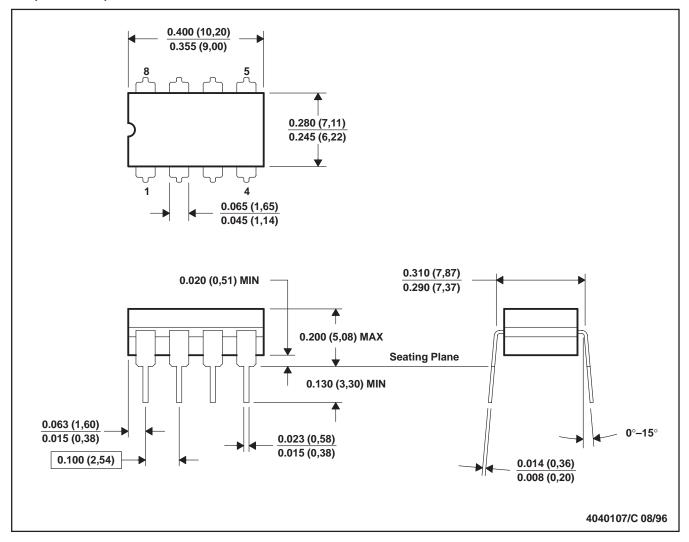
- NOTES: A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. This package can be hermetically sealed with a metal lid.
  - D. The terminals are gold plated.
  - E. Falls within JEDEC MS-004



#### **MECHANICAL INFORMATION**

## JG (R-GDIP-T8)

#### **CERAMIC DUAL-IN-LINE PACKAGE**



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL-STD-1835 GDIP1-T8



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